

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

## TC74HC273AP, TC74HC273AF

### Octal D-Type Flip Flop with Clear

The TC74HC273A is a high speed CMOS OCTAL D-TYPE FLIP FLOP fabricated with silicon gate CMOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse.

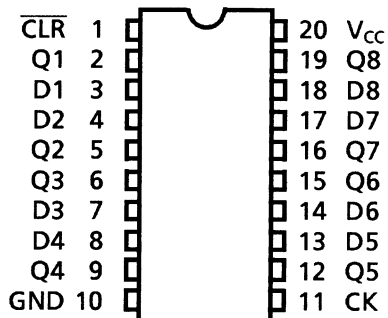
When the CLR input is held "L", the Q outputs are at a low logic level independent of the other inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

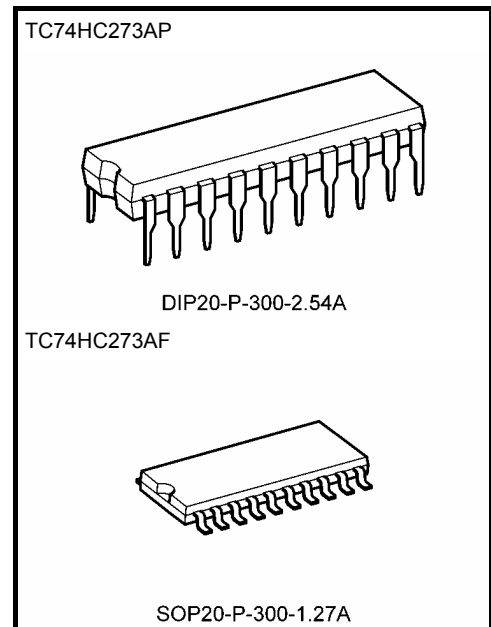
### Features

- High speed:  $f_{max} = 67$  MHz (typ.) at  $V_{CC} = 5$  V
- Low power dissipation:  $I_{CC} = 4$   $\mu$ A (max) at  $T_a = 25^\circ$ C
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\%$   $V_{CC}$  (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 4$  mA (min)
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} (opr) = 2\sim 6$  V
- Pin and function compatible with 74LS273

### Pin Assignment



(TOP VIEW)

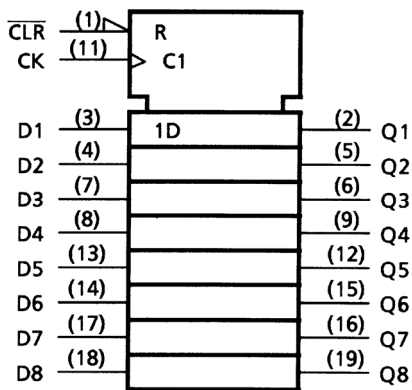


Weight

DIP20-P-300-2.54A : 1.30 g (typ.)

SOP20-P-300-1.27A : 0.22 g (typ.)

## IEC Logic Symbol

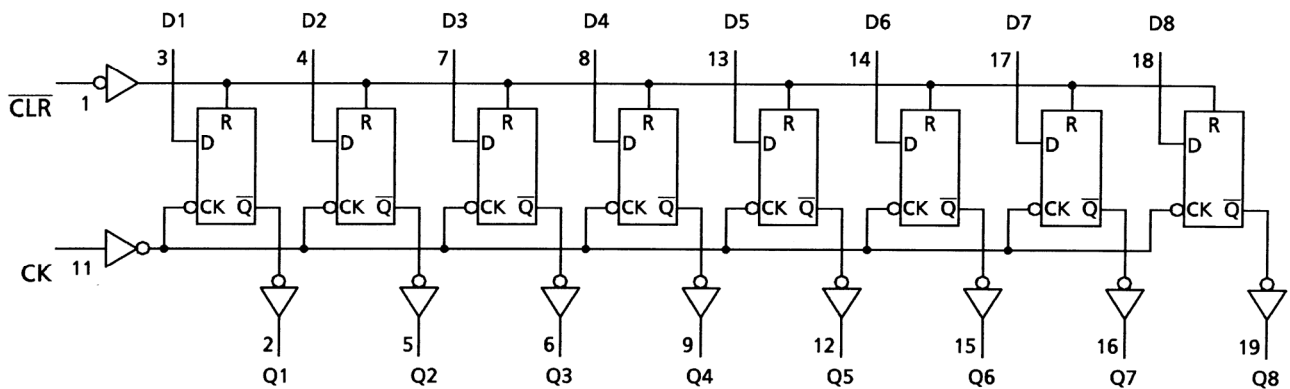


## Truth Table

Inputs			Output	Function
$\overline{\text{CLR}}$	D	CK	Q	
L	X	X	L	Clear
H	L		L	—
H	H		H	—
H	X		$Q_n$	No change

X: Don't care

## System Diagram



## Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5~7	V
DC input voltage	$V_{IN}$	-0.5~ $V_{CC} + 0.5$	V
DC output voltage	$V_{OUT}$	-0.5~ $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	±20	mA
Output diode current	$I_{OK}$	±20	mA
DC output current	$I_{OUT}$	±25	mA
DC $V_{CC}$ /ground current	$I_{CC}$	±50	mA
Power dissipation	$P_D$	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	$T_{stg}$	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of  $T_a = -40\sim 65^\circ\text{C}$ . From  $T_a = 65$  to  $85^\circ\text{C}$  a derating factor of  $-10\text{ mW}/^\circ\text{C}$  shall be applied until 300 mW.

## Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2~6	V
Input voltage	$V_{IN}$	0~ $V_{CC}$	V
Output voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	$t_r, t_f$	0~1000 ( $V_{CC} = 2.0\text{ V}$ ) 0~500 ( $V_{CC} = 4.5\text{ V}$ ) 0~400 ( $V_{CC} = 6.0\text{ V}$ )	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
				V <sub>CC</sub> (V)	Min	Typ.	Max	Min		Max
High-level input voltage	V <sub>IH</sub>	—		2.0	1.50	—	—	1.50	—	V
				4.5	3.15	—	—	3.15	—	
				6.0	4.20	—	—	4.20	—	
Low-level input voltage	V <sub>IL</sub>	—		2.0	—	—	0.50	—	0.50	V
				4.5	—	—	1.35	—	1.35	
				6.0	—	—	1.80	—	1.80	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20 μA	2.0	1.9	2.0	—	1.9	—	V
				4.5	4.4	4.5	—	4.4	—	
				6.0	5.9	6.0	—	5.9	—	
			I <sub>OH</sub> = -4 mA	4.5	4.18	4.31	—	4.13	—	
				6.0	5.68	5.80	—	5.63	—	
				I <sub>OH</sub> = -5.2 mA	4.5	—	—	—	—	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 μA	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
				6.0	—	0.0	0.1	—	0.1	
			I <sub>OL</sub> = 4 mA	4.5	—	0.17	0.26	—	0.33	
				6.0	—	0.18	0.26	—	0.33	
				I <sub>OL</sub> = 5.2 mA	4.5	—	—	—	—	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	—	—	4.0	—	40.0	μA

### Timing Requirements (input: t<sub>r</sub> = t<sub>f</sub> = 6 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C		Ta = -40~85°C	Unit	
				V <sub>CC</sub> (V)	Typ.	Limit		Limit
Minimum pulse width (CK)	t <sub>W</sub> (L) t <sub>W</sub> (H)	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum pulse width ( $\overline{\text{CLR}}$ )	t <sub>W</sub> (L)	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum set-up time	t <sub>s</sub>	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum hold time	t <sub>h</sub>	—		2.0	—	0	0	ns
				4.5	—	0	0	
				6.0	—	0	0	
Minimum removal time ( $\overline{\text{CLR}}$ )	t <sub>rem</sub>	—		2.0	—	50	65	ns
				4.5	—	10	13	
				6.0	—	9	11	
Clock frequency	f	—		2.0	—	6	5	MHz
				4.5	—	30	24	
				6.0	—	35	28	

### AC Characteristics ( $C_L = 15\text{ pF}$ , $V_{CC} = 5\text{ V}$ , $T_a = 25^\circ\text{C}$ , input: $t_r = t_f = 6\text{ ns}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}$	—	—	4	8	ns
	$t_{THL}$	—	—	4	8	ns
Propagation delay time (CK-Q)	$t_{pLH}$	—	—	15	25	ns
	$t_{pHL}$	—	—	15	25	ns
Propagation delay time ( $\overline{\text{CLR}}$ -Q)	$t_{pLH}$	—	—	16	27	ns
	$t_{pHL}$	—	—	16	27	ns
Maximum clock frequency	$f_{max}$	—	40	67	—	MHz

### AC Characteristics ( $C_L = 50\text{ pF}$ , input: $t_r = t_f = 6\text{ ns}$ )

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	$T_a = 25^\circ\text{C}$			$T_a = -40\sim 85^\circ\text{C}$		Unit
				Min	Typ.	Max	Min	Max	
Output transition time	$t_{TLH}$ $t_{THL}$	—	2.0	—	25	75	—	95	ns
			4.5	—	7	15	—	19	
			6.0	—	6	13	—	16	
Propagation delay time (CK-Q)	$t_{pLH}$ $t_{pHL}$	—	2.0	—	54	145	—	180	ns
			4.5	—	18	29	—	36	
			6.0	—	15	25	—	31	
Propagation delay time ( $\overline{\text{CLR}}$ -Q)	$t_{pLH}$ $t_{pHL}$	—	2.0	—	60	160	—	200	ns
			4.5	—	20	32	—	40	
			6.0	—	17	27	—	34	
Maximum clock frequency	$f_{max}$	—	2.0	6	18	—	5	—	MHz
			4.5	30	56	—	24	—	
			6.0	35	66	—	28	—	
Input capacitance	$C_{IN}$	—	—	5	10	—	10	pF	
Power dissipation capacitance	$C_{PD}$ (Note)	—	—	43	—	—	—	pF	

Note:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per flip flop)}$$

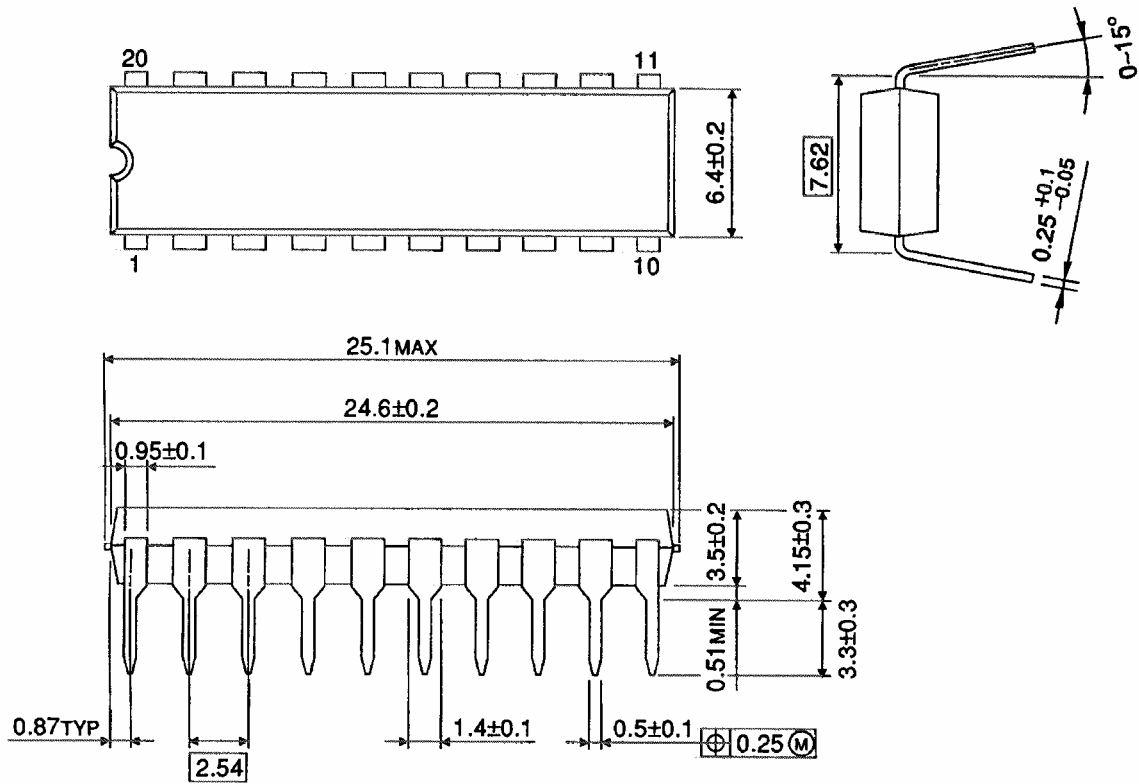
And the total  $C_{PD}$  when n pcs. of flip flop operate can be gained by the following equation:

$$C_{PD}(\text{total}) = 32 + 11 \cdot n$$

## Package Dimensions

DIP20-P-300-2.54A

Unit : mm

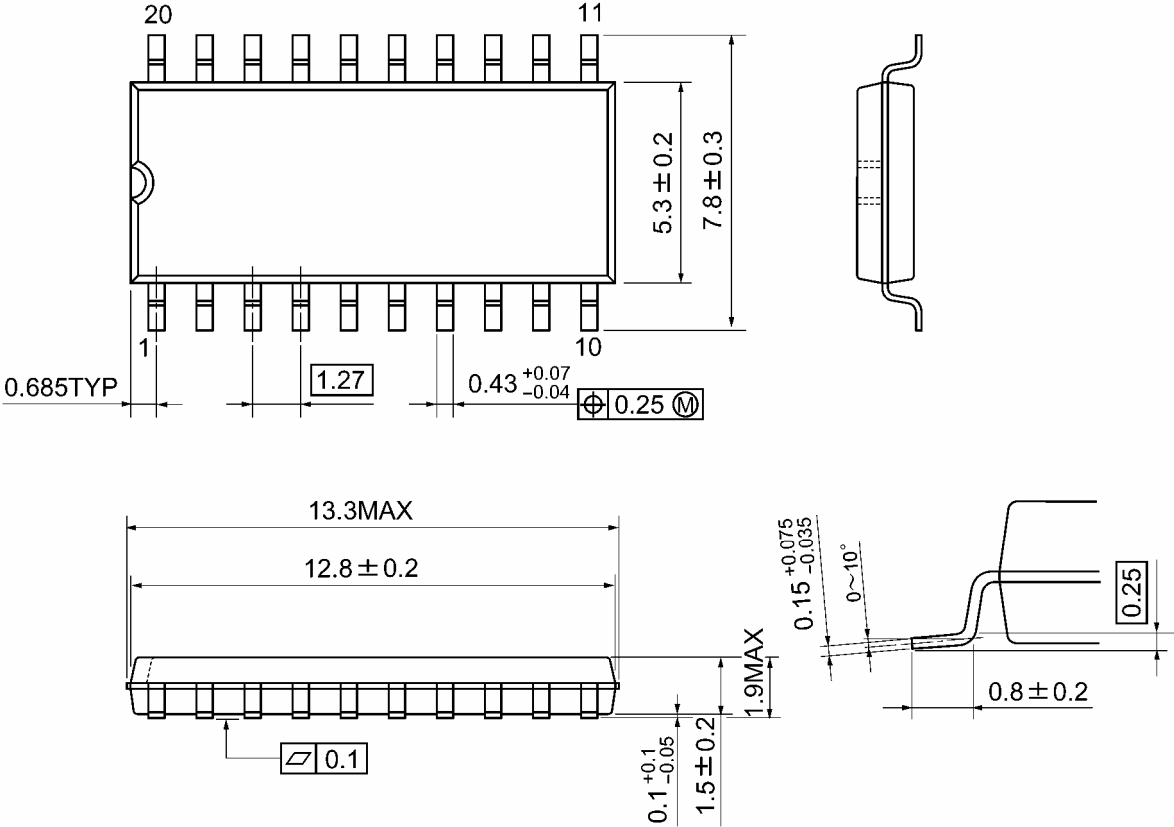


Weight: 1.30 g (typ.)

Package Dimensions

SOP20-P-300-1.27A

Unit: mm



Weight: 0.22 g (typ.)

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20070701-EN GENERAL

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